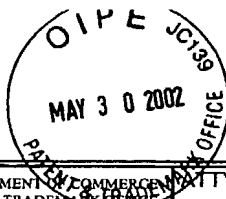


SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 220302US0		SERIAL NO. 10/091,402	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Hajime ITOH, et al.			
				FILING DATE March 7, 2002		GROUP 2879	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
OK	AA	4,919,700	04/24/90	G. A. PECORARO, et al.	←	←	
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO						
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	C. TANAKA, et al., Proceedings of the International Conference on Science and Technology of New Glasses, No. A4, XP-002141801, pps. 71-76, "REFINING OF GLASSES UNDER SUBATMOSPHERIC PRESSURES", October 16, 1991					
	AX						
	AY						
	AZ						
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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10091,402

LIST OF REFERENCES CITED BY APPLICANT

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Hajime ITOH, et al.

FILING DATE

March 7, 2002

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2879

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
ML	AA	6,332,339	12/25/2001	T. KAWAGUCHI, et al.			
CL	AB	6,294,005	09/25/2001	S. INOUE, et al.			
CL	AC	6,251,811	06/26/2001	O. YANAGISAWA, et al.			
CL	AD	6,318,126	11/20/2001	Y. TAKEI, et al.			
CL	AE	6,334,336	01/01/2002	Y. TAKEI, et al.			
CL	AF	6,308,534	10/30/2001	Y. TAKEI, et al.			
CL	AG	6,321,572	11/27/2001	Y. TAKEI, et al.			
CL	AH	6,202,445	03/20/2001	M. SUGIMOTO, et al.			
CL	AI	6,119,484	09/19/2000	Y. TAKEI, et al.			
CL	AJ	5,849,058	12/15/98	S. TAKESHITA, et al.			
CL	AK	Re. 36,082	02/09/99	K. ISHIMURA, et al.			
CL	AL	5,922,097	07/13/99	H. KOBAYASHI, et al.			
CL	AM	6,128,924	10/10/2000	J. C. BANGE, et al.			
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO	2000-128549	05/09/2000	JAPAN (with English Abstract)		X
	AP	2000-239023	09/05/2000	JAPAN (with English Abstract)		X
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

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